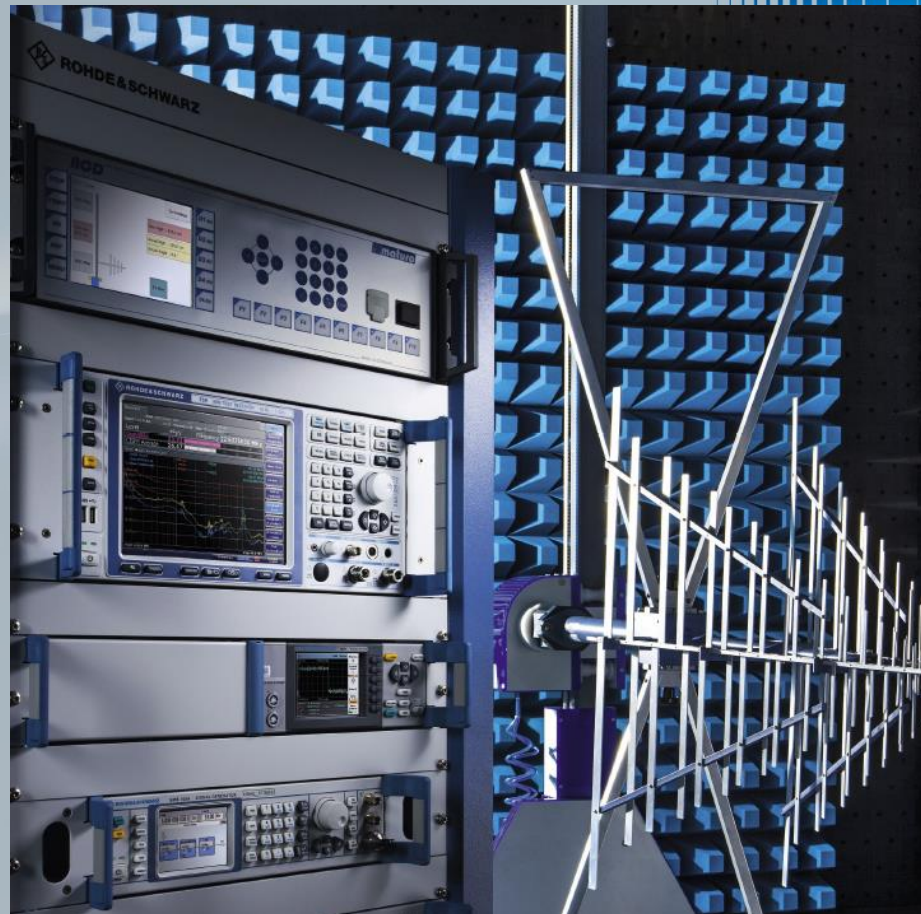


EMC-ESD in de Praktijk – 4/11/2014

Time-domain based EMI measurements



Agenda

- **Time domain based EMI measurements**
 - Introduction to EMI
 - FFT principles and possible causes for errors
 - Time Domain Scan in **EMI Receivers**
 - High speed FFT in **Oscilloscopes**

Annexes:

- Some links to YouTube
- Application Notes



Introduction to EMI

Today's Electronic Design & EMI

Nowadays electronic engineers are facing...

- Faster clock speeds & smaller form factors
- More data lines for communications
- Included RF technology (WLAN, Bluetooth, 3G/UMTS, 4G/LTE)
- Power has more impact on signals with smaller amplitude
- PCB Layout stacking – multilayer design
- Rise & fall times go down to fractions on nano-seconds
- So all this is **high frequency** up to GHz range



Introduction to EMI

Understand your electronic design

Clock rates, possible harmonics,
frequency of power supplies, shielding, grounding ...



EMC Design TOOLS

Software Prediction
Pre-scanning
Near field scanning

EMC Lab

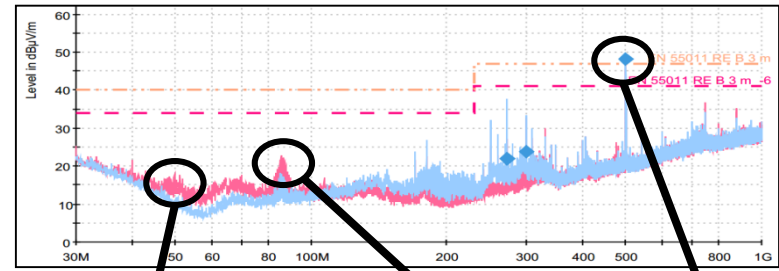
In-house testing
Outsourcing (EMC lab)
EMC Consultants



I know my system and
can solve the EMI issues



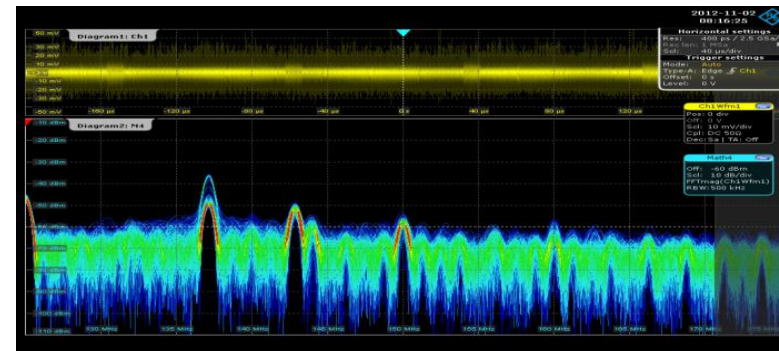
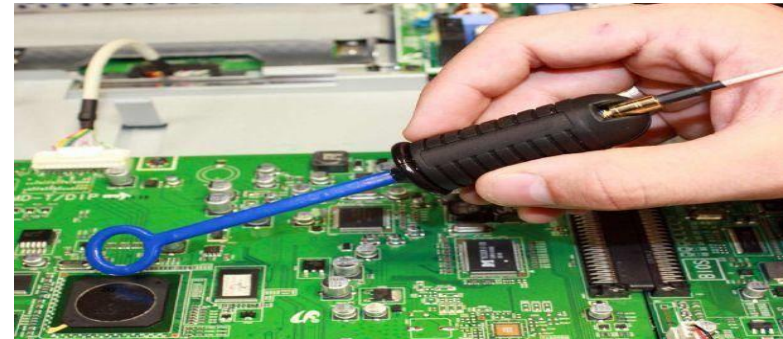
By using fast and accurate
EMI TOOLS



Noise from power supply

Unknown broadband
noise peak

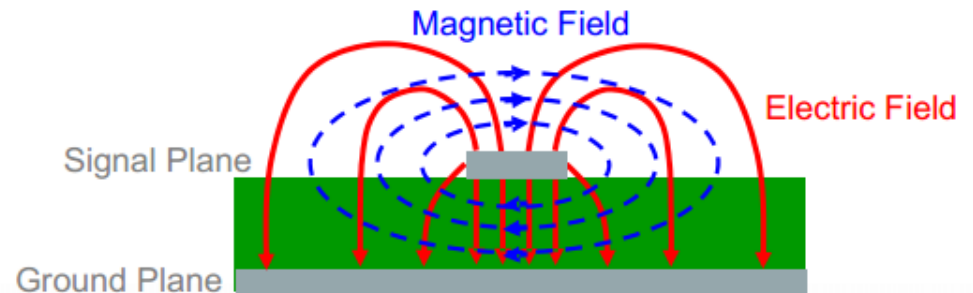
CW Emission



Introduction to EMI

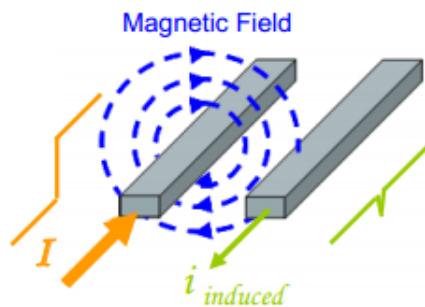
The impact of Electromagnetism

Even on a simple PCB circuit, Magnetic & Electric Fields are generated as long as current passes through the conducting medium

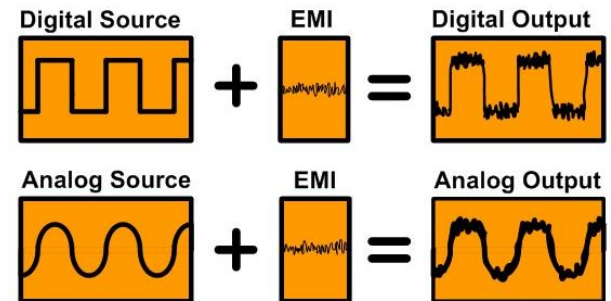
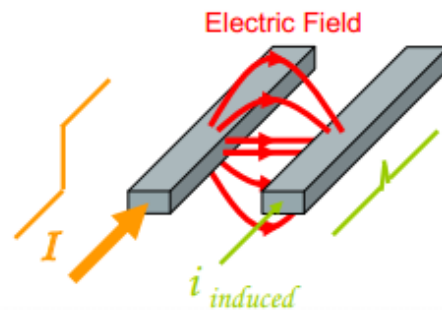


Both the E & H-field will penetrate adjacent conducting medium and induce noise on it

I Mutual Inductance



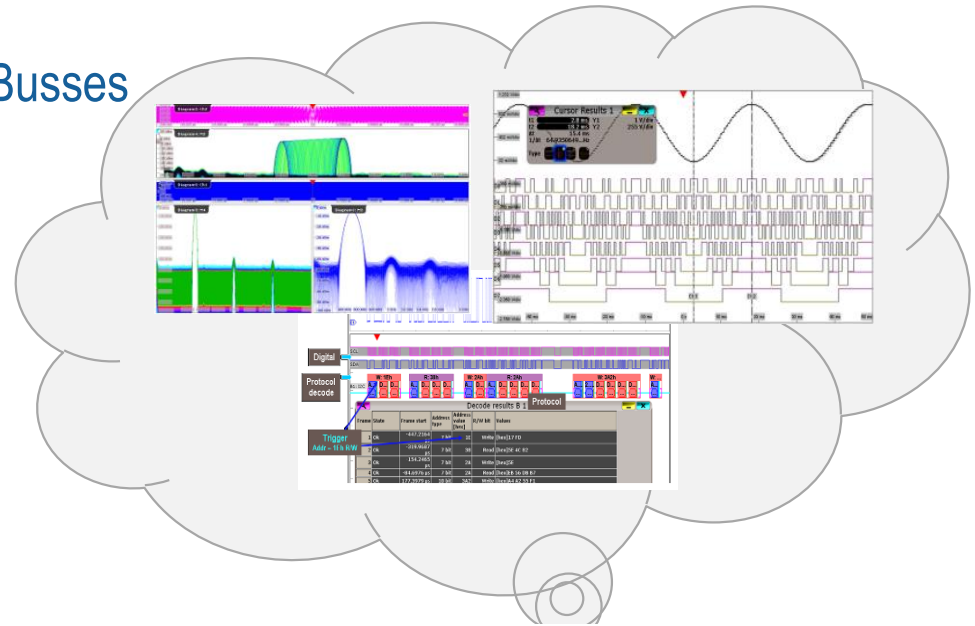
I Mutual Capacitance



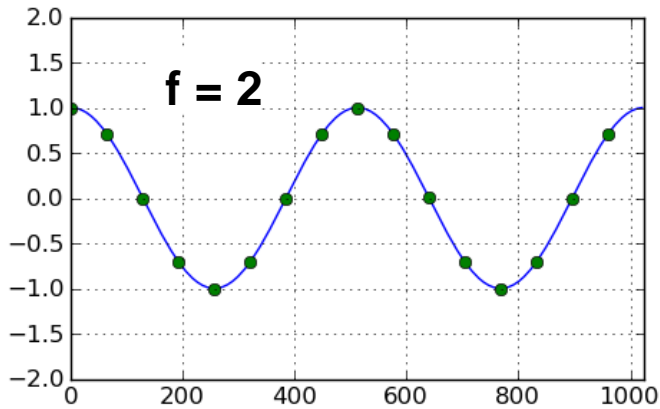
The EMI bubble... How to test efficiently?

EMC engineers are concerned about:

- Analog RF Signals, Digital High Speed Busses
- Parallel, Serial Bus Analysis & Decode
- Mix Signal Analysis
- FFT Analysis
- Triggering
- Time Correlated Events
- Acquisition rate (frequency range)
- Dead-time (missing intermittent faults)
- Dynamic Range (sensitivity)
- EMI Filters, Detectors, Windowing
- EMI Limit lines
- EMI transducer correction factors
- EMI appropriate accessories / infrastructure

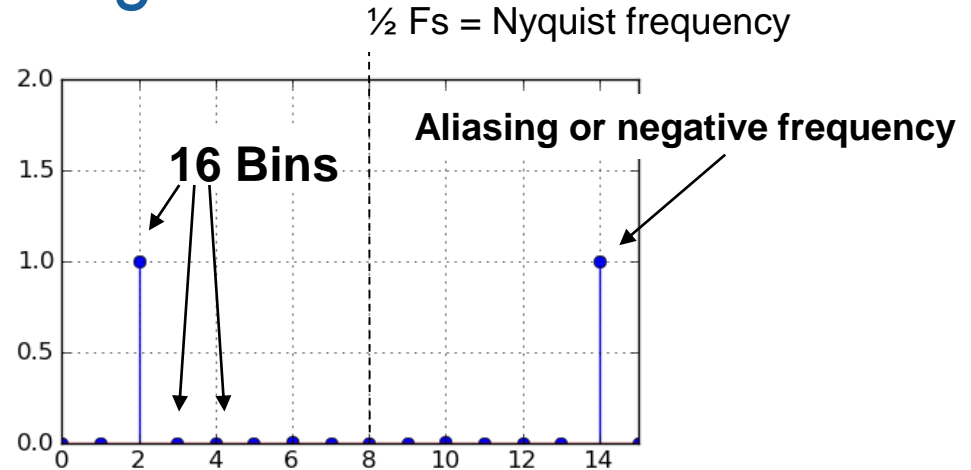


FFT Basics – Spectral Leakage

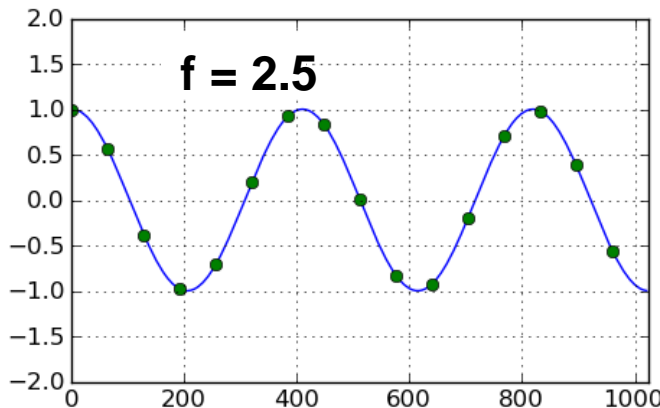


- 16 Discrete Samples in Time Domain
- Sample Frequency F_s

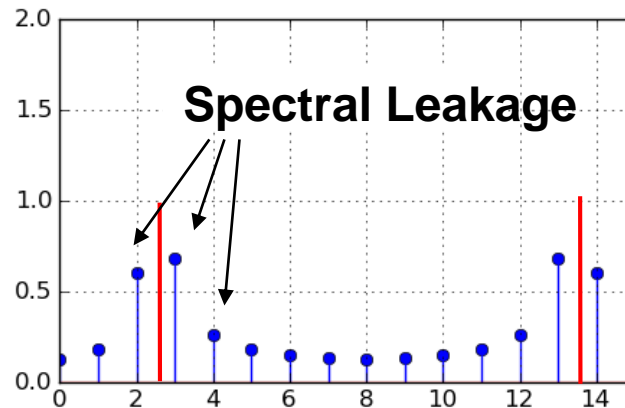
○ — ●
FFT



- 16 Discrete Frequency points in FFT
- Frequency resolution = $1/16 * F_s$



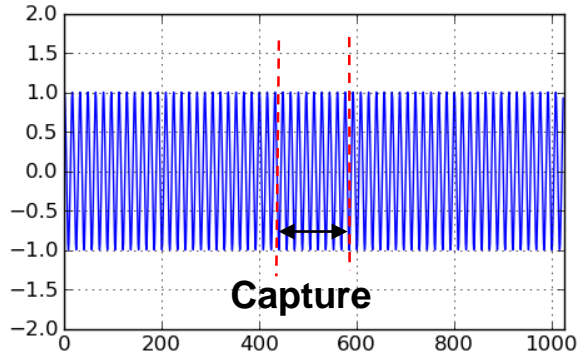
○ — ●
FFT



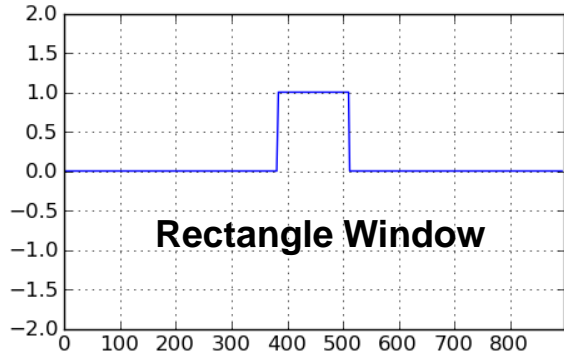
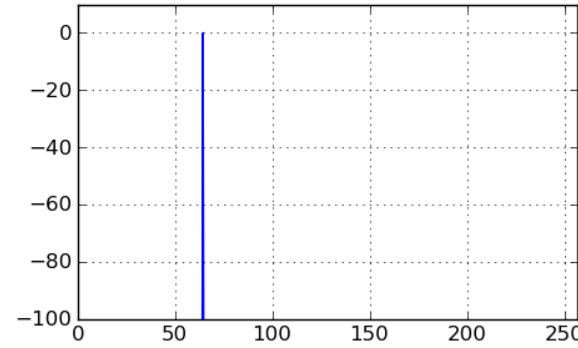
Spectral Leakage -> Signal Energy spreads over a lot of bins

FFT Basics – Solution: Windowing

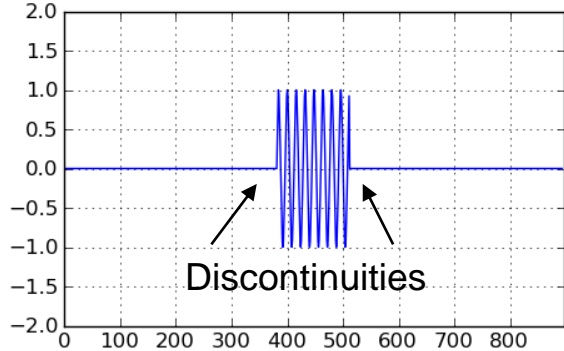
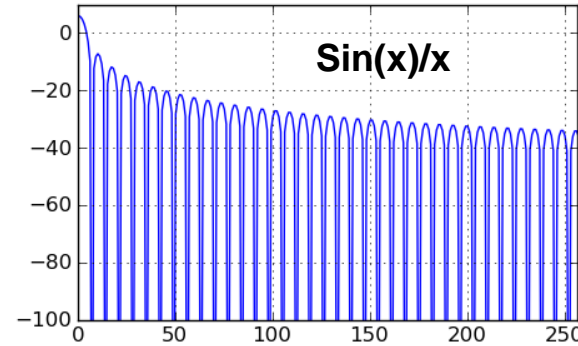
Multiplication in Time Domain



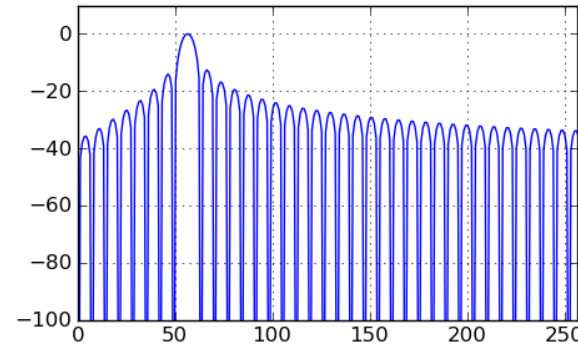
FFT



FFT



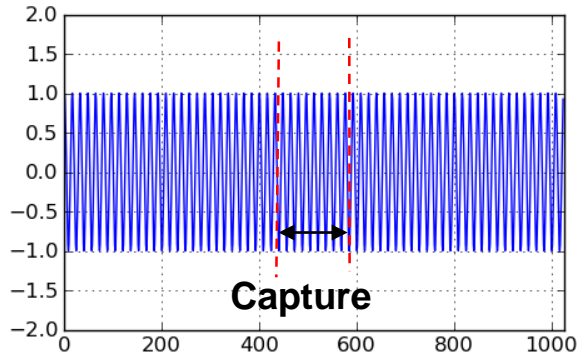
FFT



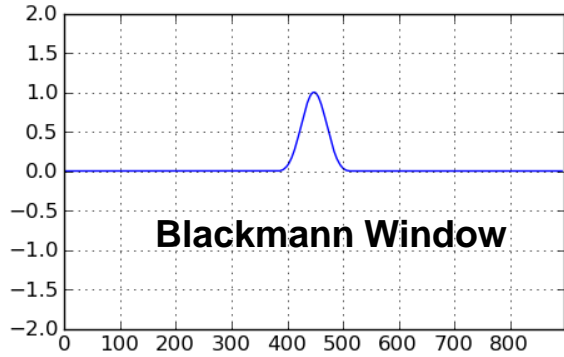
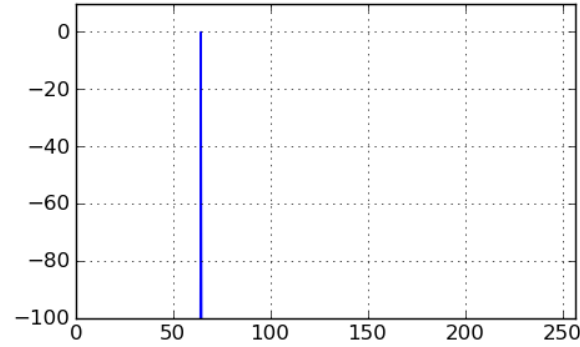
Convolution in Frequency Domain

FFT Basics - Windowing

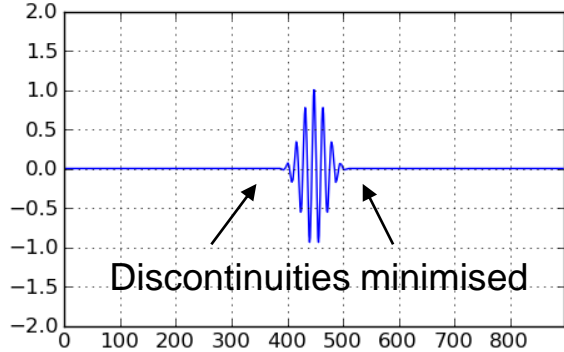
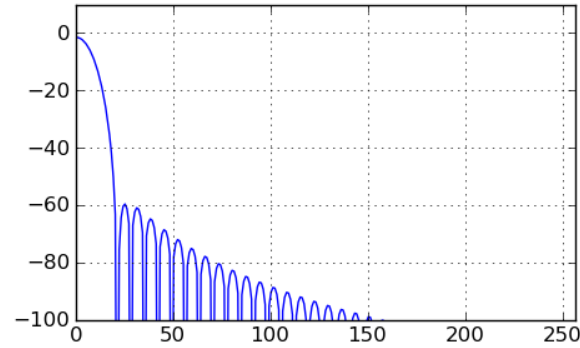
Multiplication in Time Domain



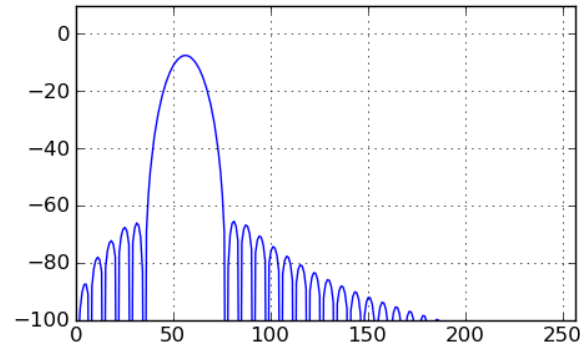
FFT



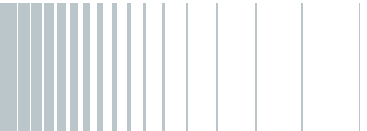
FFT



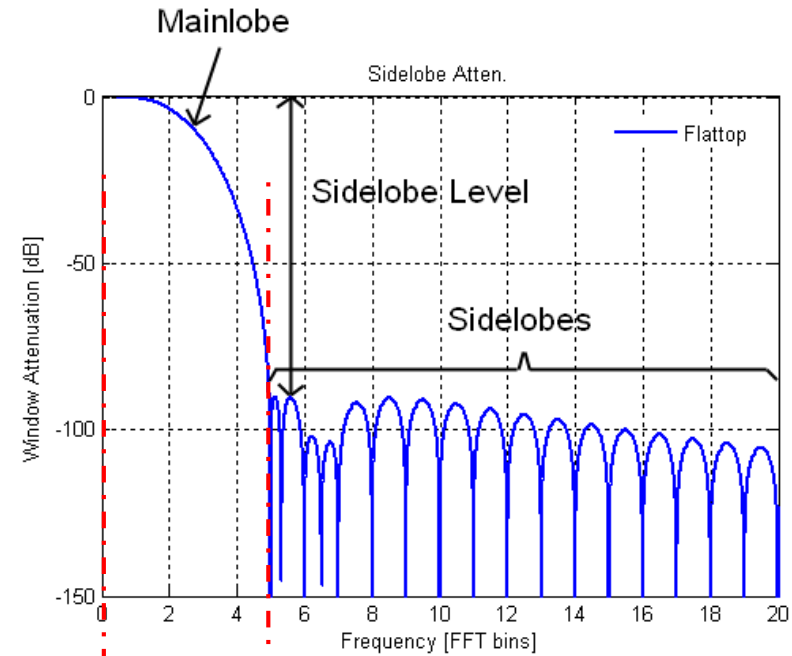
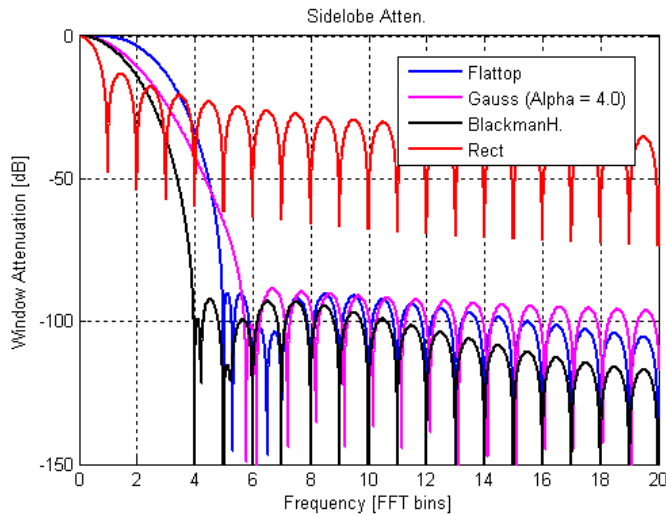
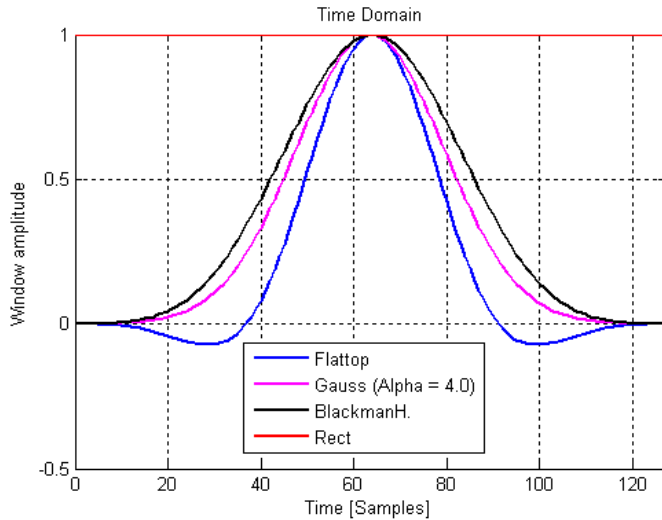
FFT



Convolution in Frequency Domain



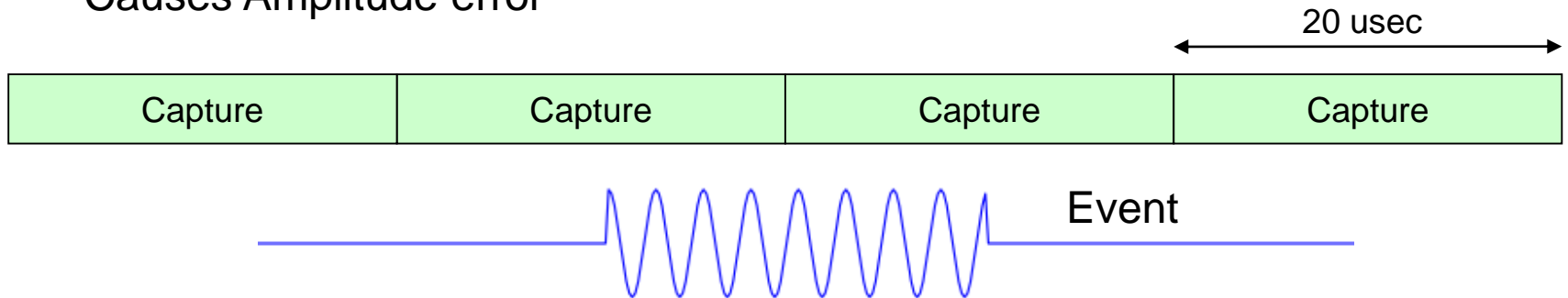
FFT Basics – Window Properties



FFT Basics – 2 Problems

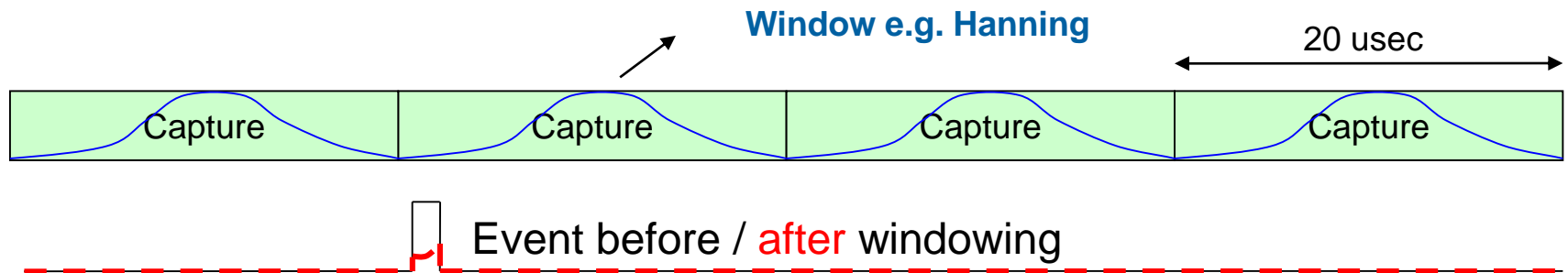
Problem 1:

- Event does not fully cover 1 Capture → 'incomplete' FFT's
- Causes Amplitude error

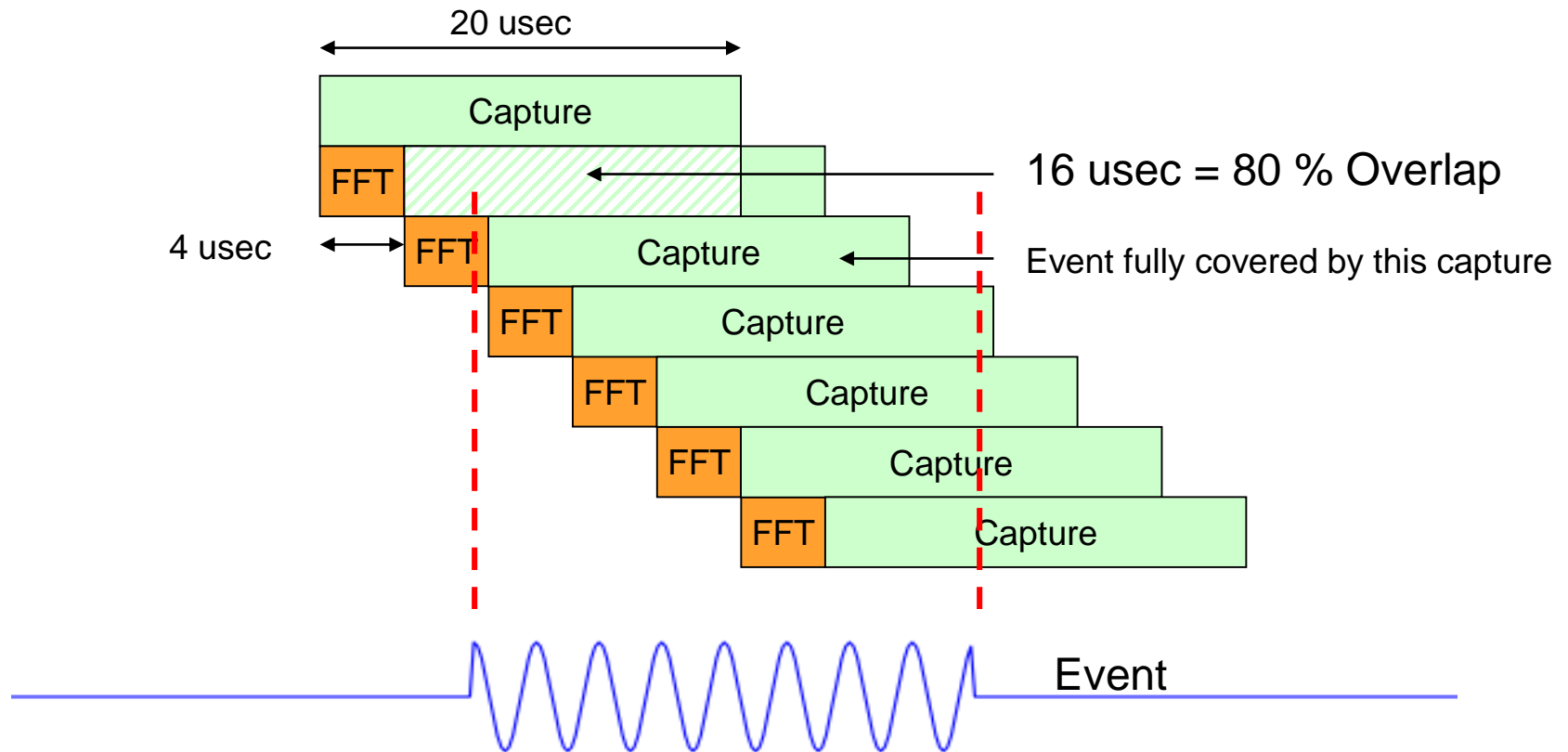


Problem 2:

- Very short Events at the edge of a window (other than Rectangle)
- Are almost not visible



FFT Basics – Solution: Overlapping

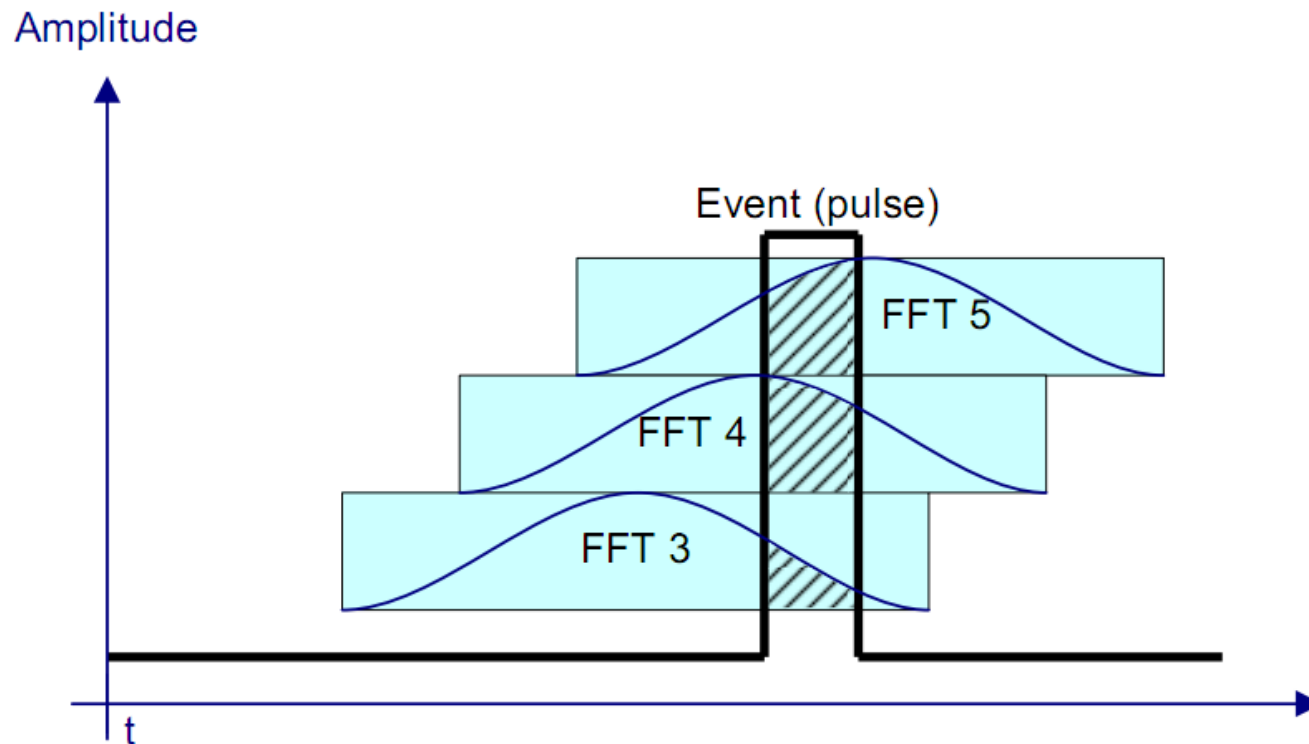


- 80% overlap ensures amplitude accuracy for events > 24 usec
- Events < 24 usec will still be detected but with too low amplitude
- Shortest detectable event defined by e.g. BW 40 MHz $\rightarrow 25$ nsec



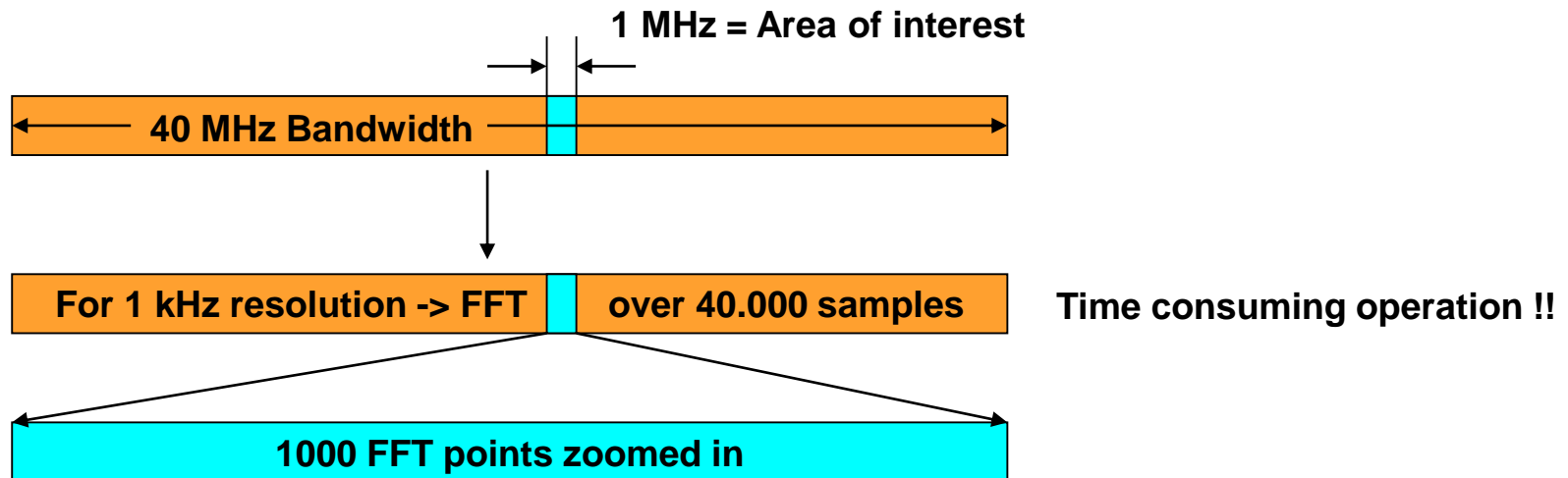
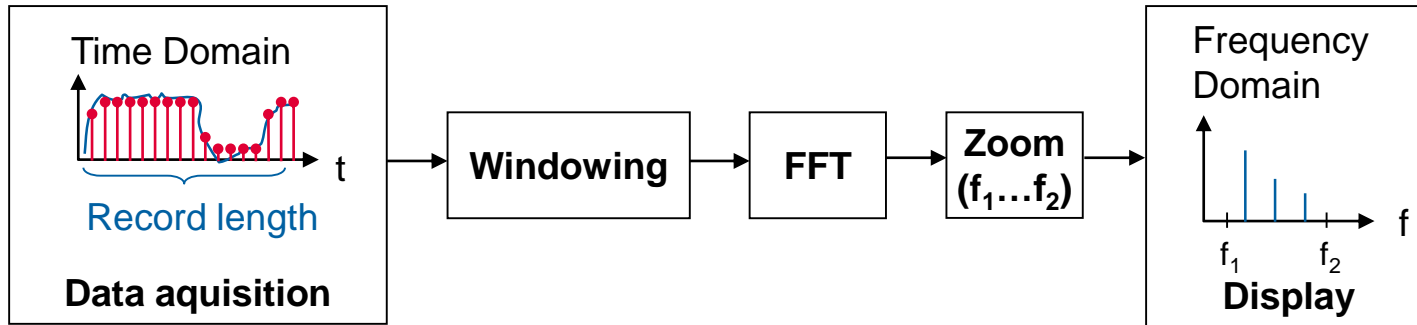
FFT Basics – Solution: Overlapping

Overlapping is also a solution for problem 2



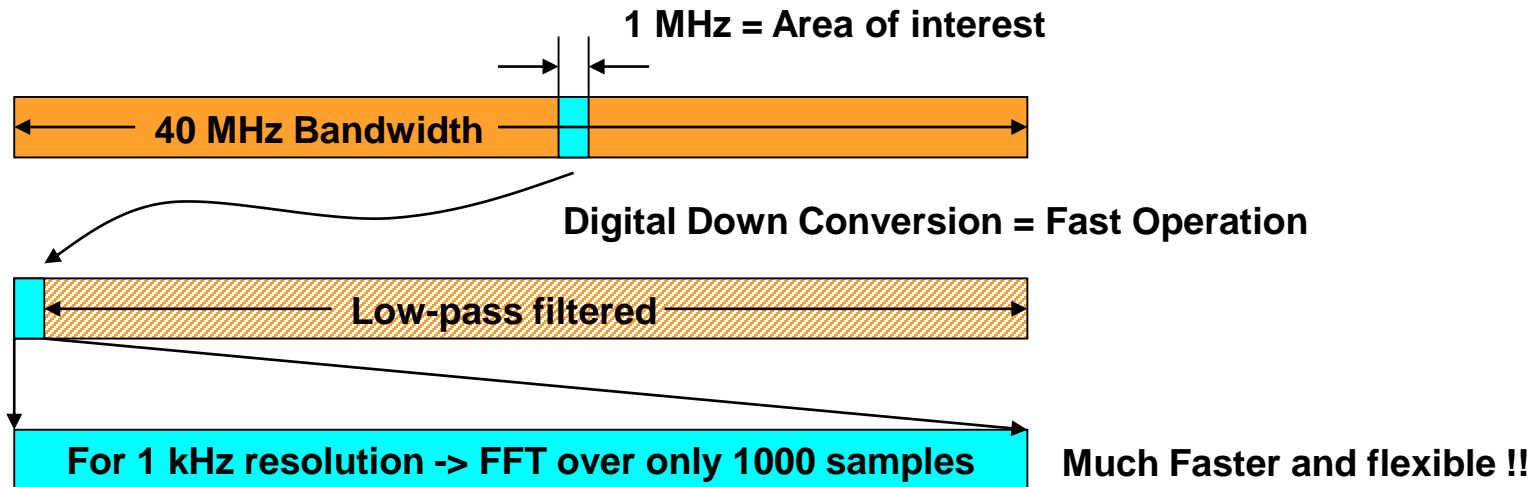
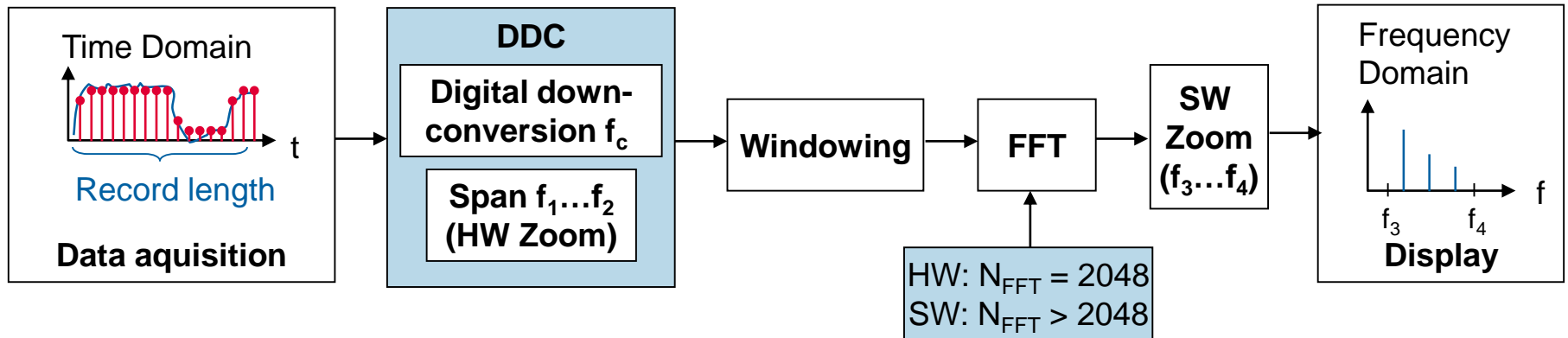
FFT Implementation - Traditional

FFT calculation on conventional instruments:



FFT Implementation – Digital Down-conversion

FFT calculation in R&S ESR(P)/RTE/RTO –with digital down-converter



R&S ESR EMI Test Receiver

key features and benefits



- I **EMI test receiver compliant to CISPR 16-1-1 Ed. 3 Amend. 1**
 - ⇒ measurement of RFI emissions to commercial EMC standards (CISPR, EN, FCC, ETS, ANSI C63.4, VCCI, etc.)
- I **Time domain scan (option) alternatively to the standard stepped frequency scan**
 - ⇒ among the fastest EMI test receivers in the marketplace
 - ⇒ direct comparison of both scan methods in one diagram
- I **Realtime capabilities (option) with up to 40 MHz span**
 - ⇒ new insights in EMC diagnostics and analysis of disturbances
- I **Spectrum analyzer mode with preselection & EMI application incl. 16 independent measurement markers**
 - ⇒ CISPR-compliant EMI measurements also in analyzer mode

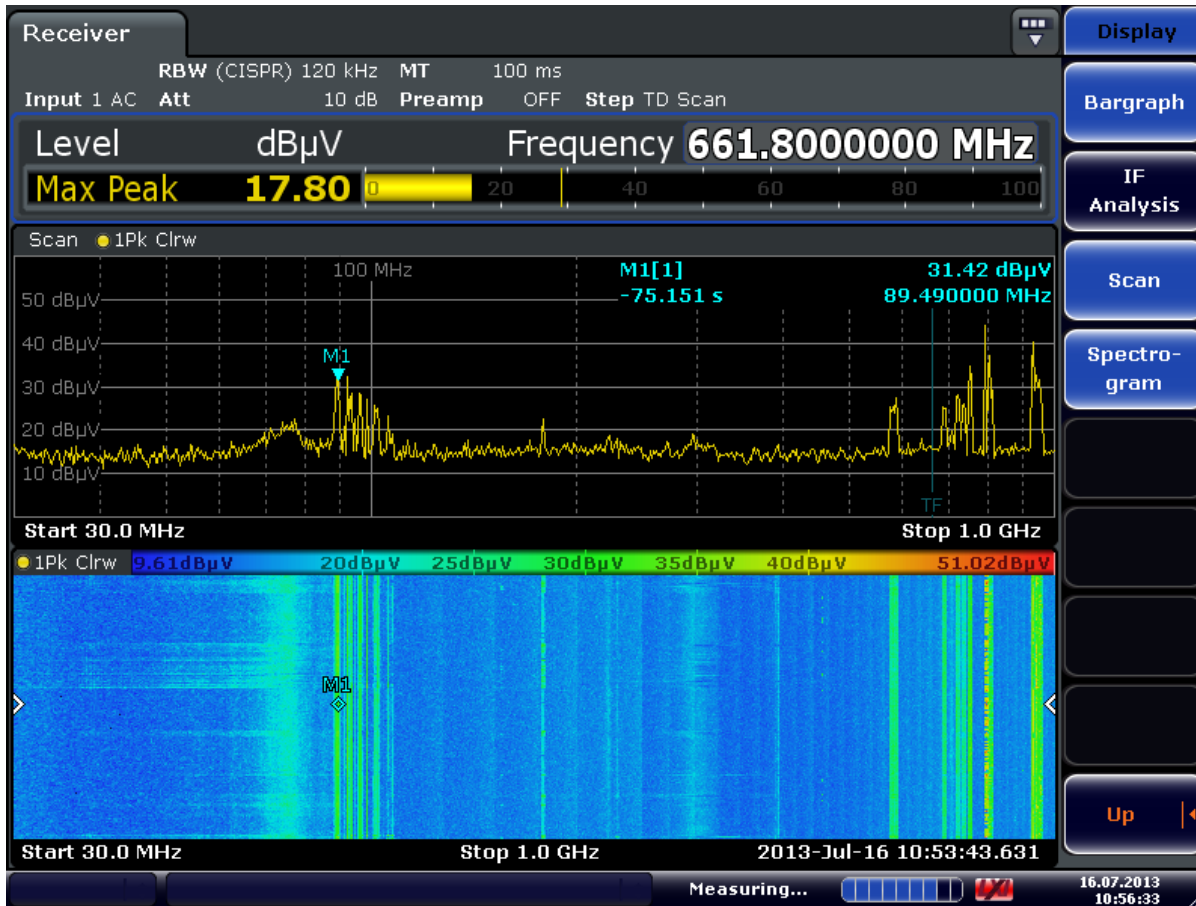
ESR(P) – Std. Stepped Scan vs. Time-Domain Scan



Fig. 16: Measured signal spectra, quasi-peak detector, 150 MHz to 30 MHz.

Trace 1 (yellow) was measured with a time domain scan, trace 2 (green) with a stepped scan.

ESR Time Domain scan spectrogram



Spectrogram in receiver mode

Spectrogram in split screen mode can be combined with:

- Time Domain scan
- Stepped Freq. scan
- IF analysis
- Bar-graph on/off

Marker evaluation

Measurement Speed EMI Receivers:

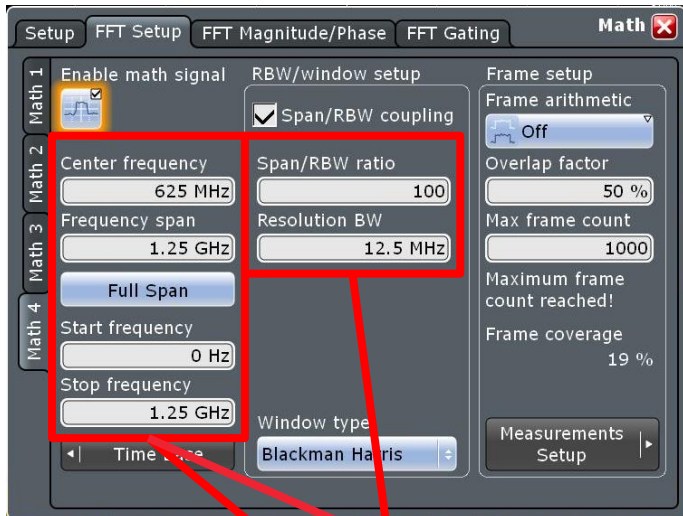
Time domain scan vs. stepped scan

Frequency range	Weighting detector, measurement time, IF BW (no. of measurement points)	R&S ESRP		R&S ESR
		Stepped frequency scan	Time domain scan (option)	Time domain scan (option)
CISPR Band B 150 k to 30 MHz	Pk, 100 ms, 9 kHz (13.267)	1.326 s	2 s	0,11 s
CISPR Band B 150 k to 30 MHz	QP, 1 s, 9 kHz (13.267)	3.6 h	60 s	2 s
Band C/D 30 to 1000 MHz	Pk, 10 ms, 120 kHz (32.334)	323 s	6 s	0,52 s
Band C/D 30 to 1000 MHz	Pk, 10 ms, 9 kHz (431.000)	4.310 s	8 s	0,82 s
Band C/D 30 to 1000 MHz	QP, 1 s, 120 kHz (32.334)	approx. 9 h	1 980 s	80 s



FFT in R&S RTE/RTO Oscilloscopes

Spectrum Analyzer Look & Feel

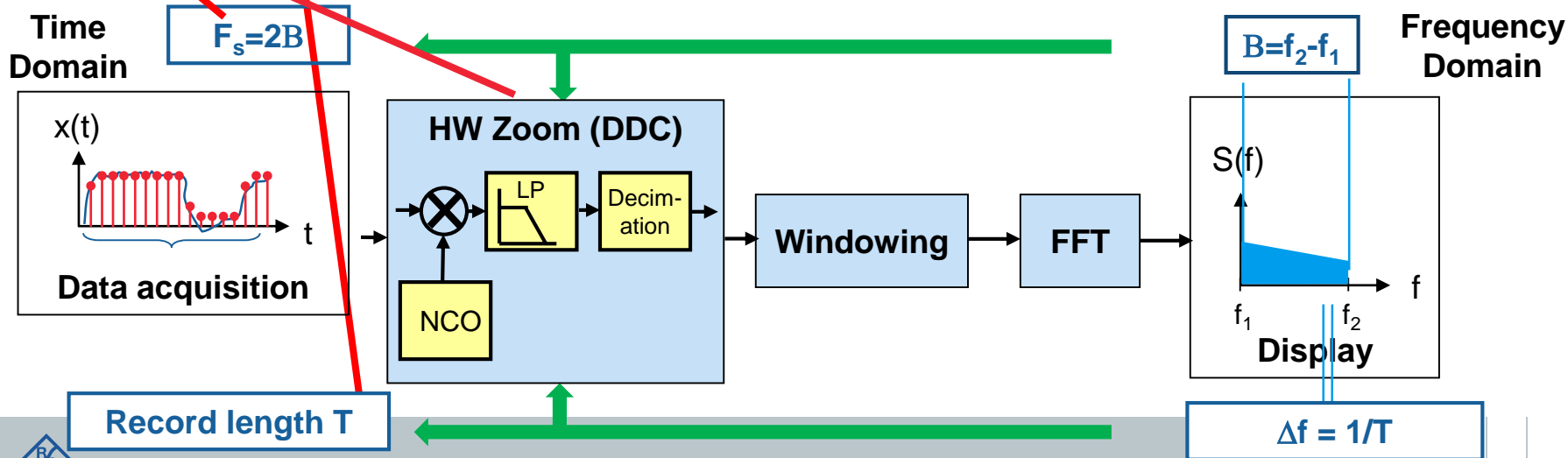


Frequency domain controls time domain

- Time domain parameters (record-length / sampling rate) automatically changed as necessary

Down-conversion FFT (DDC) zooms into frequency range *before* FFT

- Largely reduced record length, much faster FFT



EMC Applications for Oscilloscopes

EMI

EMS

Radiated Interference

Conducted Interference

Power Quality

ESD, EFT and Burst Calibration

EUT Monitoring

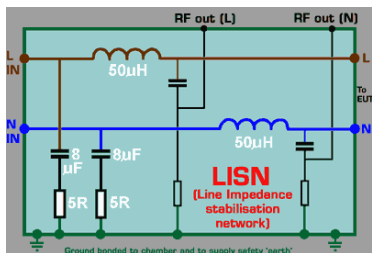
EN55011, EN55012, EN55013, EN55014, EN55015, EN55022, CISPR

EN55011, EN55012, EN55013, EN55014, EN55015, EN55022, CISPR

EN61000-3-2
EN60555-2
EN61000-3-3
EN60555-3

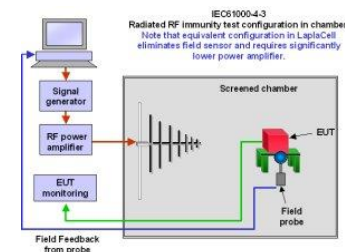
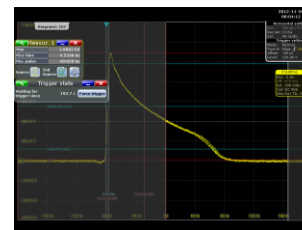
EN61000-4-2
EN61000-4-4
EN61000-4-5

EN61000-4-3



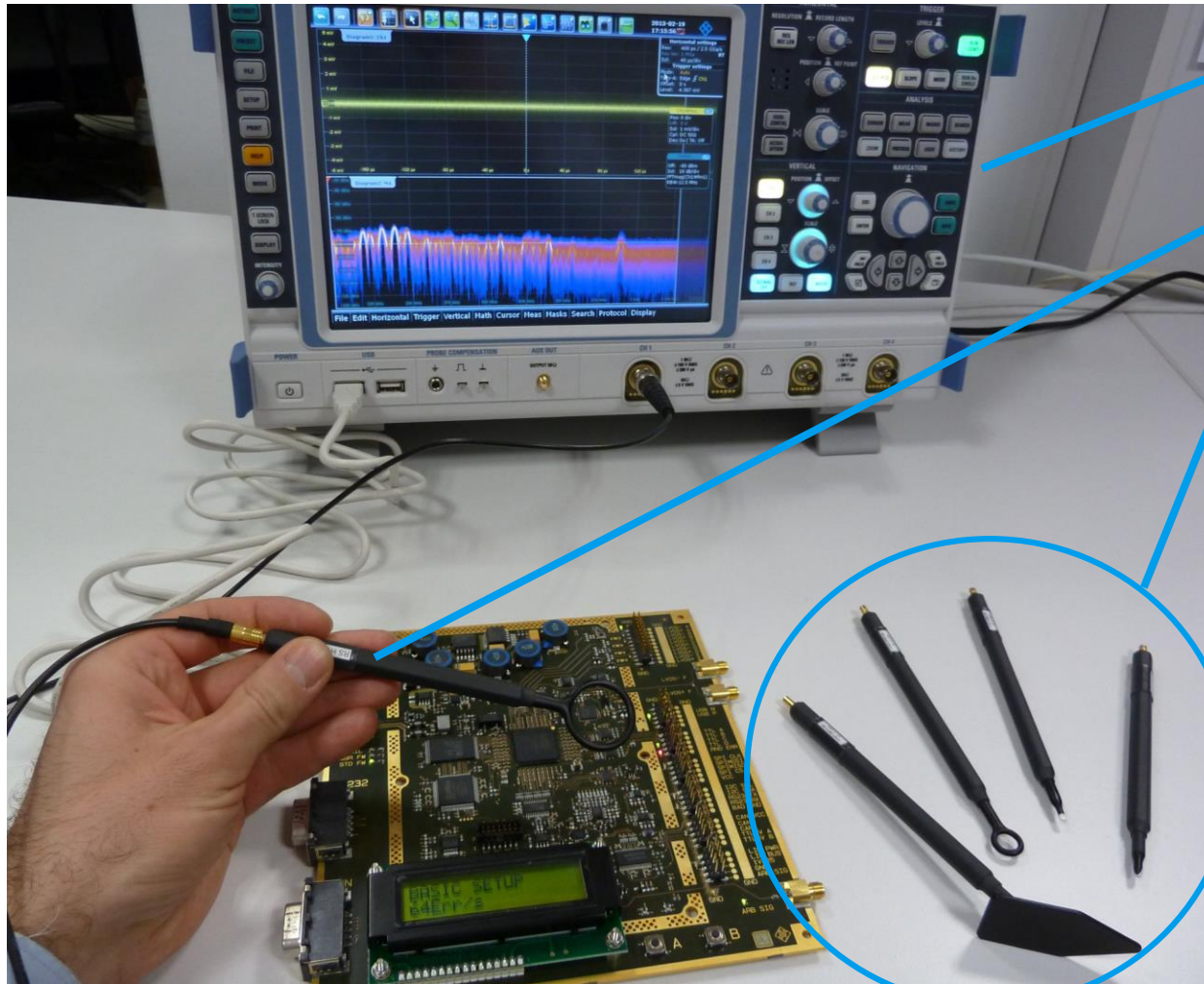
Power Harmonics

Flicker Measurement



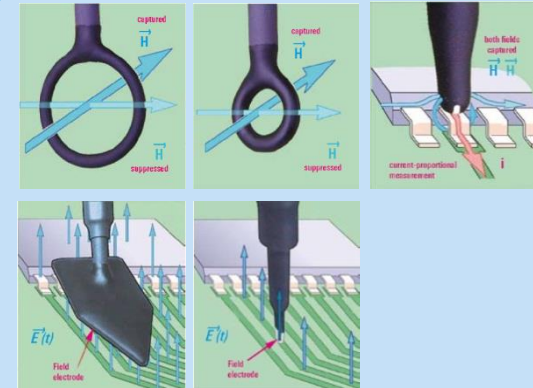
➔ RTE/RTO: A powerful tool for EMI/EMS debugging and precompl. applications

EMI Debugging with high-speed Oscilloscope



R&S ® RTO

**Near-field sniffer
Probes R&S ® HZ-15**
E- and H-field



30 MHz – 1 GHz
Can be used down to 100 kHz

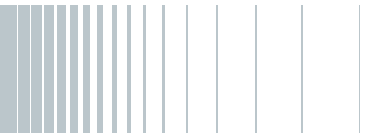
Optional:
R&S ® HZ-16
Pre-amplifier

EMC & RTE/RTO

www.rohde-schwarz.com or google on YouTube

Some useful links....:

- **R&S®RTO Oscilloscope Spectrum Sensitivity and FFT Capability**
 - <http://www.youtube.com/watch?v=LHAdy9oo0Uo>
- **R&S®RTO oscilloscope frequency analysis part 1 (3): The implementation**
 - <http://www.youtube.com/watch?v=SrWFmL12RQc>
- **R&S®RTO oscilloscope frequency analysis part 2 (3): AM and FM**
 - <http://www.youtube.com/watch?v=SrWFmL12RQc>
- **R&S®RTO oscilloscope frequency analysis part 3 (3): Frequency, time**
 - <http://www.youtube.com/watch?v=HaWqSCapZwU>
- **R&S®RTO Intuitive User Interface and Operation**
 - <http://www.youtube.com/watch?v=xFO3rPHGGNY>
- **R&S®RTO Family, the digital oscilloscopes from Rohde & Schwarz**
 - http://www.youtube.com/watch?v=rrYEFtgK_kg



Application Notes

Comparison of Time Domain Scans and Stepped Frequency Scans in EMI Test Receivers

http://www.rohde-schwarz.com/en/applications/comparison-of-time-domain-scans-and-stepped-frequency-scans-in-emi-test-receivers-application-note_56280-54019.html

EMI Debugging with the R&S®RTO and R&S®RTE Oscilloscopes

http://www.rohde-schwarz.com/en/applications/emi-debugging-with-the-r-s-rto-and-r-s-rte-oscilloscopes-application-note_56280-58049.html



Thank you for your attention !



Any questions

Rohde & Schwarz Nederland B.V.
Rohde & Schwarz Belgium N.V.

Perkinsbaan 1 · 3439ND Nieuwegein · The Netherlands
Excelsiorlaan 32 b1 · B-1930 Zaventem · Belgium
Tel (NL) +31 30 600 1700 / (B) +32 2 704 4040
Fax (NL) +31 30 600 1799 / (B) +32 2 725 0936
E-Mail: info.nl@rohde-schwarz.com
Website: www.rohde-schwarz.com
Webshop: www.testenmeetwinkel.nl